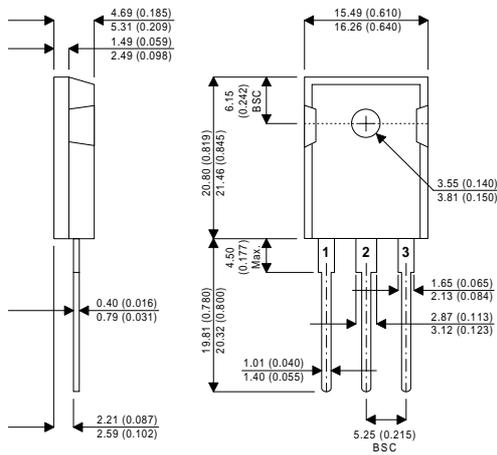


4TH GENERATION MOSFET

TO247–AD Package Outline.
Dimensions in mm (inches)



**N-CHANNEL
ENHANCEMENT MODE
HIGH VOLTAGE
POWER MOSFETS**

V_{DSS} 500V
 $I_{D(cont)}$ 23.0A
 $R_{DS(on)}$ 0.25 Ω

Terminal 1 Gate **Terminal 2** Drain
Terminal 3 Source

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

| | | | |
|----------------|--|------------|-------------|
| V_{DSS} | Drain – Source Voltage | 500 | V |
| I_D | Continuous Drain Current | 23 | A |
| I_{DM} | Pulsed Drain Current ¹ | 92 | A |
| V_{GS} | Gate – Source Voltage | ± 30 | V |
| P_D | Total Power Dissipation @ $T_{case} = 25^{\circ}C$ | 310 | W |
| T_J, T_{STG} | Operating and Storage Junction Temperature Range | -55 to 150 | $^{\circ}C$ |
| T_L | Lead Temperature : 0.063" from Case for 10 Sec. | 300 | |

STATIC ELECTRICAL RATINGS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

| | Characteristic | Test Conditions | Min. | Typ. | Max. | Unit |
|--------------|--|--|------|------|-----------|----------|
| BV_{DSS} | Drain – Source Breakdown Voltage | $V_{GS} = 0V, I_D = 250\mu A$ | 500 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current ($V_{GS} = 0V$) | $V_{DS} = V_{DSS}$ | | | 250 | μA |
| | | $V_{DS} = 0.8V_{DSS}, T_C = 125^{\circ}C$ | | | 1000 | |
| I_{GSS} | Gate – Source Leakage Current | $V_{GS} = \pm 30V, V_{DS} = 0V$ | | | ± 100 | nA |
| $V_{GS(TH)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = 1.0mA$ | 2 | | 4 | V |
| $I_{D(ON)}$ | On State Drain Current ² | $V_{DS} > I_{D(ON)} \times R_{DS(ON)}^{Max}$ $V_{GS} = 10V$ | 23 | | | A |
| $R_{DS(ON)}$ | Drain – Source On State Resistance ² | $V_{GS} = 10V, I_D = 0.5 I_D [Cont.]$ | | | 0.25 | Ω |

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Pulse Test: Pulse Width < 380 μS , Duty Cycle < 2%

DYNAMIC CHARACTERISTICS

| | Characteristic | Test Conditions | Min. | Typ. | Max. | Unit |
|--------------|--------------------------------|----------------------------------|------|------|------|------|
| C_{iss} | Input Capacitance | $V_{GS} = 0V$ | | 2380 | 2950 | pF |
| C_{oss} | Output Capacitance | $V_{DS} = 25V$ | | 522 | 730 | |
| C_{rss} | Reverse Transfer Capacitance | $f = 1MHz$ | | 196 | 290 | |
| Q_g | Total Gate Charge ³ | $V_{GS} = 10V$ | | 83 | 130 | nC |
| Q_{gs} | Gate – Source Charge | $V_{DD} = 0.5 V_{DSS}$ | | 12.6 | 19 | |
| Q_{gd} | Gate – Drain (“Miller”) Charge | $I_D = I_D [Cont.] @ 25^\circ C$ | | 51 | 76 | |
| $t_{d(on)}$ | Turn-on Delay Time | $V_{GS} = 15V$ | | 14 | 28 | ns |
| t_r | Rise Time | $V_{DD} = 0.5 V_{DSS}$ | | 27 | 55 | |
| $t_{d(off)}$ | Turn-off Delay Time | $I_D = I_D [Cont.] @ 25^\circ C$ | | 61 | 92 | |
| t_f | Fall Time | $R_G = 1.8\Omega$ | | 36 | 71 | |

SOURCE – DRAIN DIODE RATINGS AND CHARACTERISTICS

| | Characteristic | Test Conditions | Min. | Typ. | Max. | Unit |
|----------|------------------------------------|--|------|------|------|---------|
| I_S | Continuous Source Current | (Body Diode) | | | 23 | A |
| I_{SM} | Pulsed Source Current ¹ | (Body Diode) | | | 92 | |
| V_{SD} | Diode Forward Voltage ² | $V_{GS} = 0V, I_S = -I_D [Cont.]$ | | | 1.3 | V |
| t_{rr} | Reverse Recovery Time | $I_S = -I_D [Cont.], di_S / dt = 100A/\mu s$ | 160 | 320 | 640 | ns |
| Q_{rr} | Reverse Recovery Charge | | 2.7 | 5.5 | 11 | μC |

SAFE OPERATING AREA CHARACTERISTICS

| | Characteristic | Test Conditions | Min. | Typ. | Max. | Unit |
|----------|---------------------------|--|------|------|------|------|
| SOA1 | Safe Operating Area | $V_{DS} = 0.4V_{DSS}, t = 1 \text{ Sec.}$ $I_{DS} = P_D / 0.4V_{DSS}$ | 310 | | | W |
| SOA2 | Safe Operating Area | $V_{DS} = P_D / I_D [Cont.]$ $I_{DS} = I_D [Cont.], t = 1 \text{ Sec.}$ | 310 | | | W |
| I_{LM} | Inductive Current Clamped | | 92 | | | A |

THERMAL CHARACTERISTICS

| | Characteristic | Min. | Typ. | Max. | Unit |
|-----------------|---------------------|------|------|------|--------------|
| $R_{\theta JC}$ | Junction to Case | | | 0.40 | $^\circ C/W$ |
| $R_{\theta JA}$ | Junction to Ambient | | | 40 | |

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Pulse Test: Pulse Width < 380 μs , Duty Cycle < 2%

3) See MIL–STD–750 Method 3471



CAUTION — Electrostatic Sensitive Devices. Anti-Static Procedures Must Be Followed.

Figure 1
MAXIMUM EFFECTIVE TRANSIENT THERMAL IMPEDANCE, JUNCTION – CASE vs PULSE DURATION

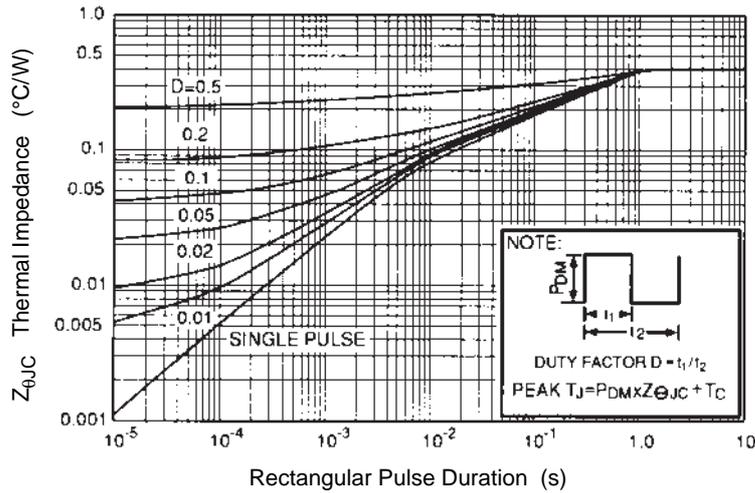


Figure 2
TYPICAL OUTPUT CHARACTERISTICS

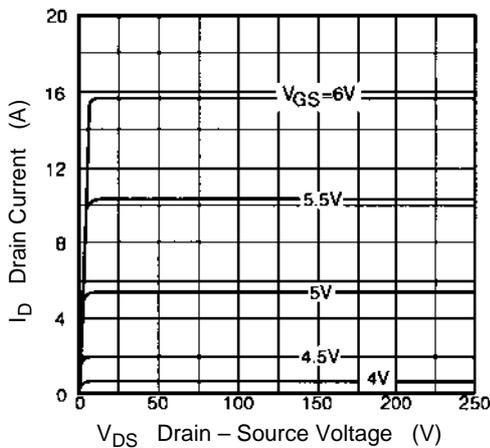


Figure 3
TYPICAL OUTPUT CHARACTERISTICS

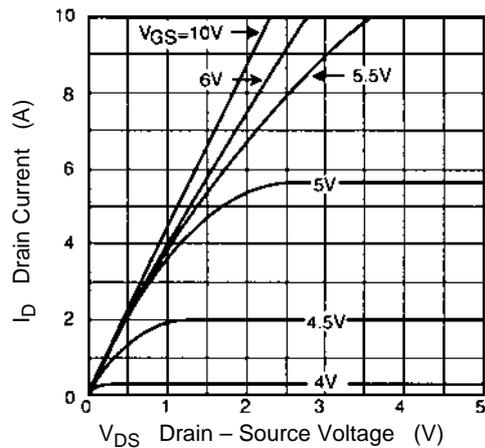


Figure 4
TYPICAL TRANSFER CHARACTERISTICS

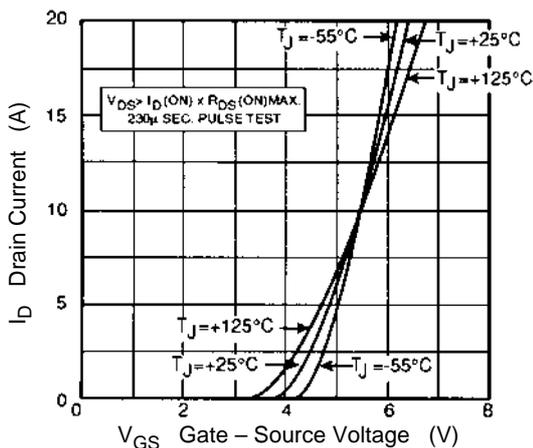


Figure 5
 $R_{DS(ON)}$ vs DRAIN CURRENT

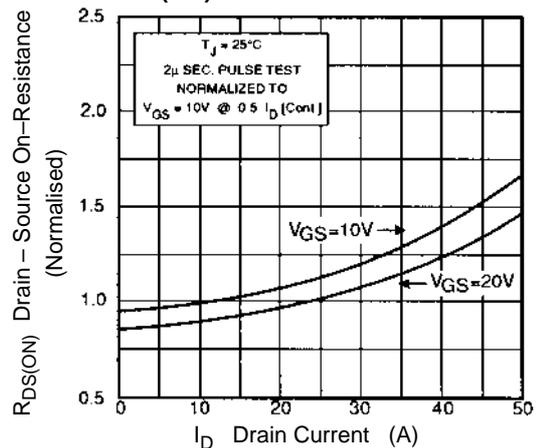


Figure 6
MAXIMUM DRAIN CURRENT vs
CASE TEMPERATURE

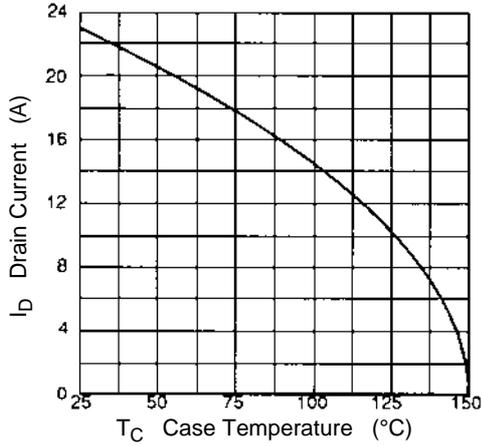


Figure 7
BREAKDOWN VOLTAGE vs TEMPERATURE

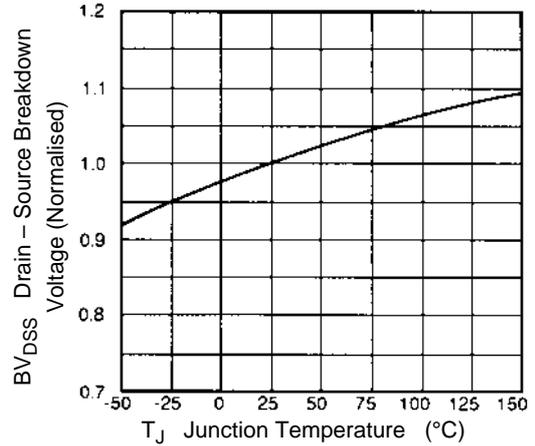


Figure 8
ON RESISTANCE vs TEMPERATURE

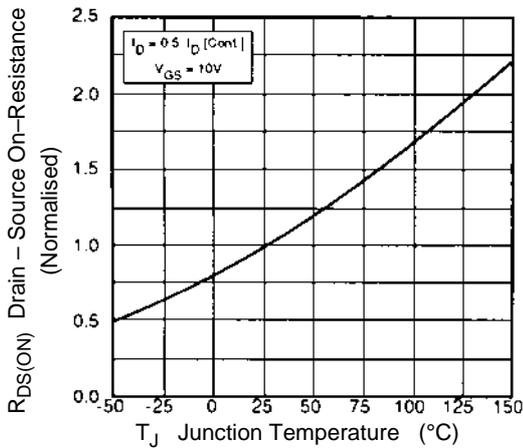


Figure 9
THRESHOLD VOLTAGE vs TEMPERATURE

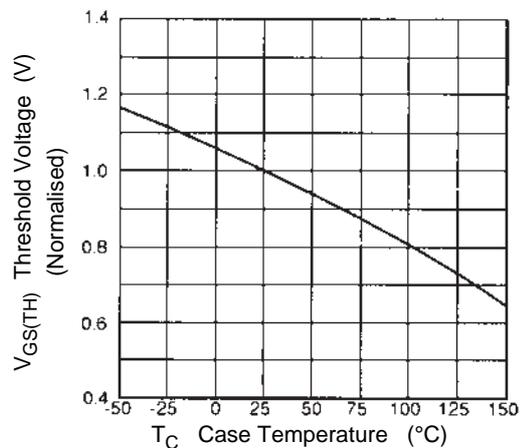


Figure 10
MAXIMUM SAFE OPERATING AREA

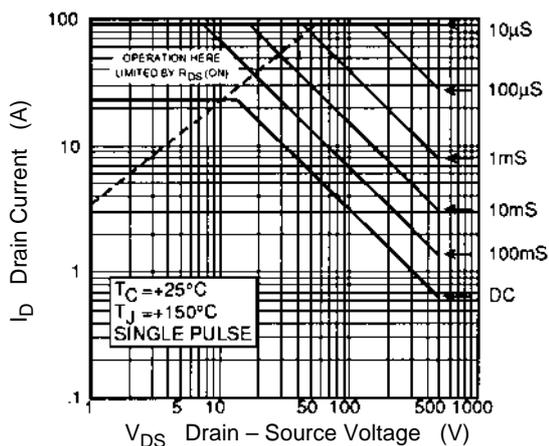


Figure 11
TYPICAL CAPACITANCE vs
DRAIN - SOURCE VOLTAGE

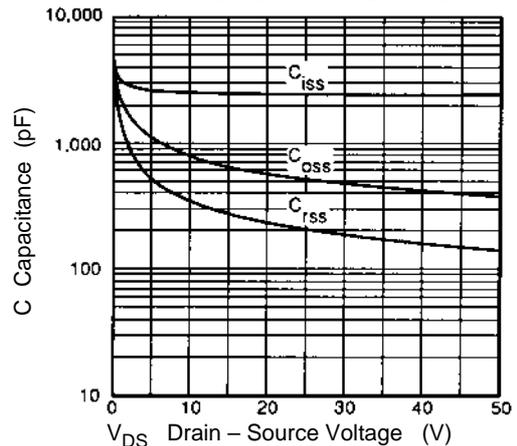


Figure 12
GATE CHARGES vs GATE – SOURCE VOLTAGE

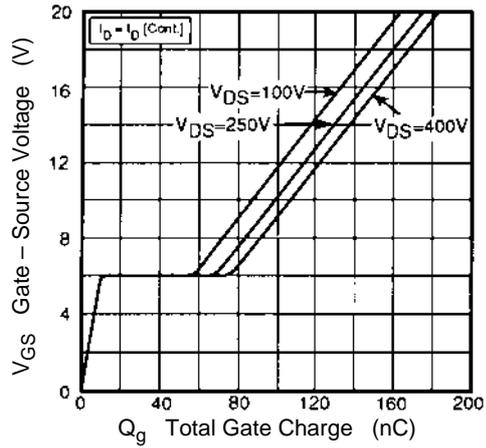


Figure 13
TYPICAL SOURCE – DRAIN DIODE FORWARD VOLTAGE

